# **Supplementary materials**

# Near-zero waste process for the recovery of palladium from a spent Pd/TiO<sub>2</sub> catalyst through a sequential process of mild acidic leaching and photodeposition on ZnO nanoparticles

## Authors

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### 1. DRUV-vis spectroscopy

**Table S** – **1.**  $E_g$  values (eV) detected for all the tested photocatalysts.

Sample	E <sub>g</sub> (eV)	
Commercial ZnO	3.18	
ZnO-S Air 200°C	3.23	
ZnO-S Air 500°C	3.25	
ZnO-S N <sub>2</sub> 200°C	3.26	
ZnO-H	3.23	
ZnO-S Air 200°C-II	3.27	
ZnO-S Air 200°C-III	3.26	



**Figure S – 1.** Diffractogram of ZnO-H sample.

3. SEM



**Figure S – 2.** SEM images of ZnO – S Air 200°C I (A, B) and ZnO – S Air 200°C II (C, D)) prepared through solgel synthesis.



**Figure S – 3.** SEM images of commercial Pd/ZnO sample, recovered after the reaction.

### 4. TEM - Particle size distribution



**Figure S – 4.** TEM micrograph images with their corresponding particle size distribution histogram for palladium recovered through photodeposition at lower (top) and higher magnification (bottom).



**Figure S – 5.** TEM micrograph images with their corresponding particle size distribution histogram for ZnO-H nanorods at lower (A) and higher magnification (B).